

What is claimed is:

1. A method for measuring particles in a glass substrate, comprising the steps of:

5 (a) sequentially conveying a plurality of glass substrates;

(b) scanning with a camera a unit area of a glass substrate in a direction of a travel path of the glass substrate and storing particle information thereof, wherein
10 the camera is placed above a travel path of the glass substrates and a scan width thereof is preset;

(c) shifting the camera in a direction perpendicular to the travel path of the glass substrate to a position corresponding to a next unit area for a succeeding glass
15 substrate;

(d) storing information on the particles in the unit area of the succeeding glass substrate obtained by scanning the glass substrate using the shifted camera;

(e) estimating whether a sum of the respective scanned
20 unit areas is within an allowed limit of an area of a glass substrate; and

(f) returning to step (c) if an answer from step (e) is "No" or storing information on the particles in the entire glass substrate obtained by summing up the
25 information on the particles in the respective scanned unit areas if the answer is "Yes".

2. The method of claim 1, wherein the plurality of glass substrates is conveyed by being floated by air jets.

5 3. The method of claim 1, further comprising the step of displaying the information stored at steps (b), (d) and/or (f).

4. The method of claim 1, further comprising the step of
10 notifying a user if a number of particles measured at step (b) and/or (d) is equal to or larger than a preset number.

5. The method of claim 1, further comprising the step of
15 notifying a user if the number of particles estimated for an entire area of the glass substrate obtained at step (f) is equal to or greater than a preset number.